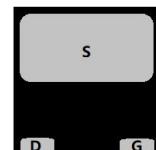
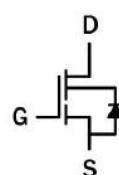
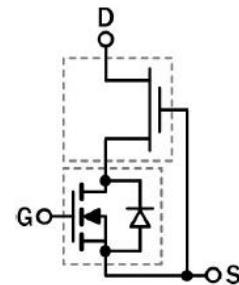


**MGZ31N65**

650V GaN FET Enhancement Mode

## Features

- 650V, 6.5A,  $R_{DS(on)}$ (typ.) = 250m $\Omega$ @VGS = 8V.
- Very low QRR
- Reduced Crossover Loss
- RoHS Compliant and Halogen-free Packaging

**PQFN8\*8  
Bottom View****Cascode Schematic Symbol****Cascode Device Structure**

## Application

- Power adapters
- Low power SMPS
- Lighting

## Absolute Maximum Ratings (Tc = 25° C unless otherwise noted)

Symbol	Parameter	Limit	Unit
		PQFN8*8	
V <sub>DS</sub>	Drain-Source Voltage	650	V
V <sub>(TR)DSS</sub>	Transient Drain to Source Voltage <sup>a</sup>	725	V
V <sub>GSS</sub>	Gate-Source Voltage	± 18	V
P <sub>D</sub>	Maximum power Dissipation @T <sub>C</sub> = 25°C	21	W
I <sub>D</sub>	Drain Current-Continuous T <sub>C</sub> = 25°C <sup>b</sup>	6.5	A
	Drain Current-Continuous T <sub>C</sub> = 100°C <sup>b</sup>	4.0	A
I <sub>DM</sub>	Drain Current-Pulsed Pulse Width = 10μs	30	A
T <sub>c</sub>	Operating Temperature Case	-55 to +150	°C
T <sub>J</sub>	Operating Temperature Junction	-55 to +150	°C
T <sub>s</sub>	Storage Temperature	-55 to +150	°C
T <sub>SOLD</sub>	Soldering Peak Temperature <sup>c</sup>	260	°C

## Thermal Characteristics

Symbol	Parameter	Typical	Unit
R <sub>θJC</sub>	Thermal Resistance Junction-Case	5.9	°C/W
R <sub>θJA</sub>	Thermal Resistance Junction-Ambient	50	°C/W

**MGZ31N65**

650V GaN FET Enhancement Mode

**Electrical Characteristics (  $T_J = 25^\circ C$  unless otherwise noted)****■ Off Characteristics**

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
$V_{(BL)DSS}$	Reverse Breakdown Voltage	$V_{GS} = 0V$	650	-	-	V
$I_{DSS}$	Reverse Leakage Current	$V_{GS} = 0V, V_{DS} = 650V$	-	-	15	$\mu A$
$I_{GSS}$	Gate-to-source Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 18V$	-	-	$\pm 100$	nA

**■ On Characteristics**

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 500\mu A$	1.1	2.0	2.9	V
$R_{DS(on)eff}$	On Resistance	$V_{GS} = 8V, I_D = 5A$	-	250	330	$m\Omega$
		$V_{GS} = 8V, I_D = 5A, T_J = 150^\circ C$	-	500	-	

**■ Dynamic Characteristics**

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
$C_{iss}$	Input Capacitance	$V_{GS} = 0V,$ $V_{DS} = 400V$ $f=1MHz$	-	760	-	pF
$C_{oss}$	Output Capacitance		-	16	-	
$C_{rss}$	Transfer Capacitance		-	2	-	
$C_{o(er)}$	Output Capacitance, energy related	$V_{GS} = 0V,$ $V_{DS} = 0\sim 400V$	-	24	-	pF
$C_{o(tr)}$	Output Capacitance, time related		-	47	-	

**■ On Characteristics**

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-On Delay Time	$V_{GS} = 0\sim 8V,$ $V_{DS} = 400V,$ $I_D = 4A,$ $R_g = 30\Omega$	-	20	-	ns
$t_r$	Turn-On Rise Time		-	4	-	
$t_{d(off)}$	Turn-Off Delay Time		-	52	-	
$t_f$	Turn-Off Fall Time		-	10	-	
$Q_G$	Total Gate Charge	$V_{GS} = 0\sim 8V,$ $V_{DS} = 400V,$ $I_D = 4A$	-	9.5	-	nC
$Q_{GS}$	Gate-Source Charge		-	2.7	-	
$Q_{GD}$	Gate-Drain Charge		-	2.5	-	
$Q_{oss}$	Output Charge	$V_{GS}=0V, V_{DS}=0\sim 400V$	-	19	-	nC

**MGZ31N65**

650V GaN FET Enhancement Mode

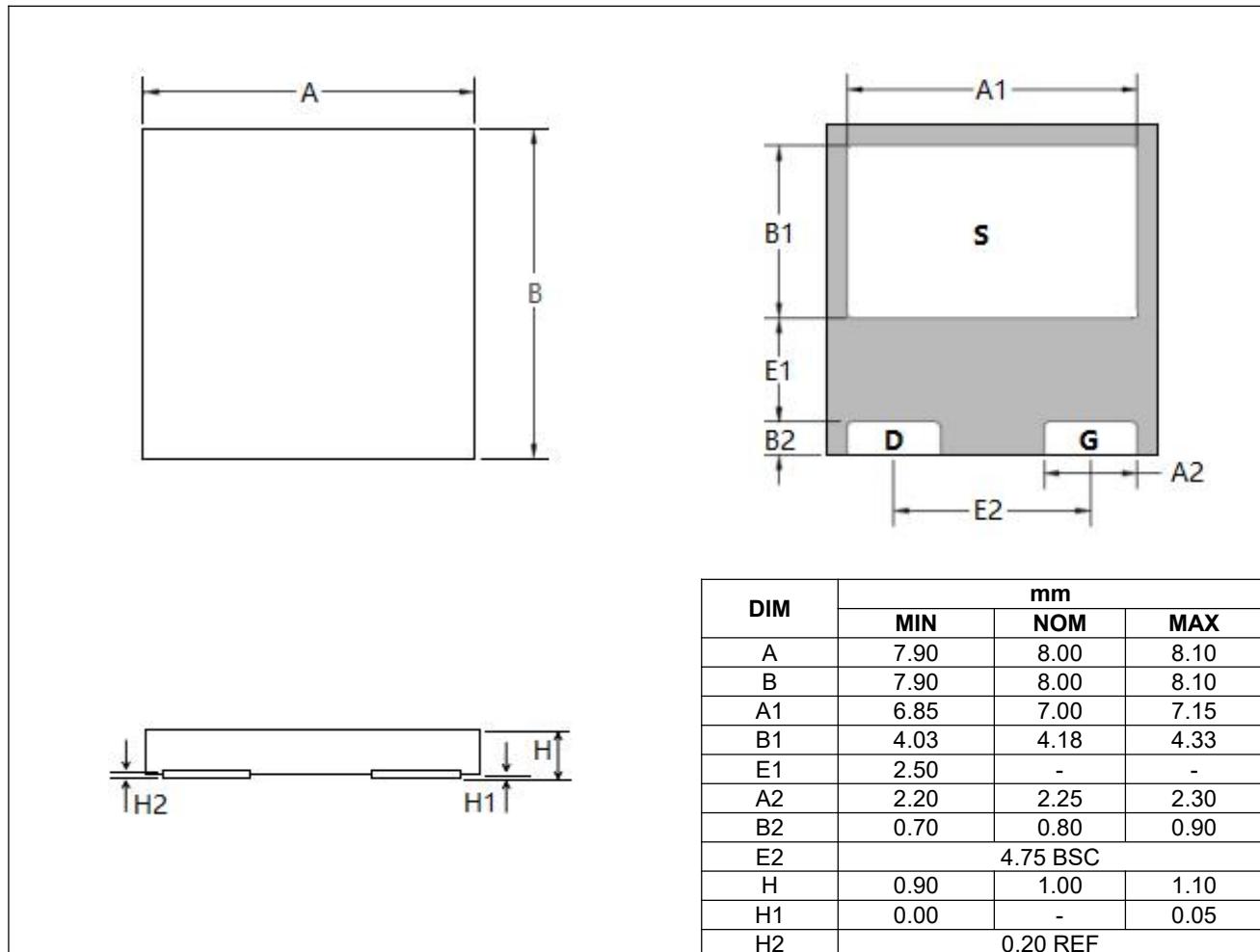
**■ Drain-Source Diode Characteristics**

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
I <sub>S</sub>	Reverse Current	V <sub>GS</sub> = 0 V, T <sub>C</sub> =100 °C, ≤25% duty cycle	-	-	4.0	A
V <sub>SD</sub>	Reverse Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 2 A	-	1.2	-	V
		V <sub>GS</sub> = 0V, I <sub>S</sub> = 4 A	-	1.6	-	V
t <sub>RR</sub>	Reverse Recovery Time	I <sub>S</sub> = 4 A ,V <sub>DS</sub> = 400V, di/dt = 1000 A/μs	-	15	-	ns
Q <sub>RR</sub>	Reverse Recovery Charge		-	22	-	nC

Notes:

- a. In off-state, spike duty cycle D<0.01, spike duration <1 μ s
- b. For increased stability at high current operation
- c. Reflow MSL3

## ■ PQFN8X8 Package Information



## ■ Revision History

Version	Date	Subjects (major changes since last revision)
0.1	2021-05-07	Preliminary version